Search Notes		

 Application/Control No.	Applicant(s)/Patent under Reexamination	
09/754,441	YOSHIHARA ET AL.	
Examiner	Art Unit	
Hai V. Nguyen	2142	

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SEARCHED			
Class	Subclass	Date	Examiner
709	205, 245	1/20/2007	ни
84	622	1/20/2007	HN

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST Search updated (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	1/20/2007	HN
Limited Classified search: 709/205, 245; 84/622 (see search history printout report)	1/20/2007	HN